

512 K (32 K x 16) Static RAM

Features

- Pin-and function-compatible with CY7C1020CV33
- High speed

 □ t_{AA} = 10 ns
- Low active power
 □ I_{CC} = 60 mA @ 10 ns
- Low CMOS standby power
 □ I_{SB2} = 3 mA
- 2.0 V Data retention
- Automatic power-down when deselected
- CMOS for optimum speed/power
- Independent control of upper and lower bits
- Available in Pb-free 44-pin 400-Mil wide Molded SOJ and 44-pin TSOP II packages

Functional Description

The CY7C1020DV33 is a high-performance CMOS static RAM organized as 32,768 words by 16 bits. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

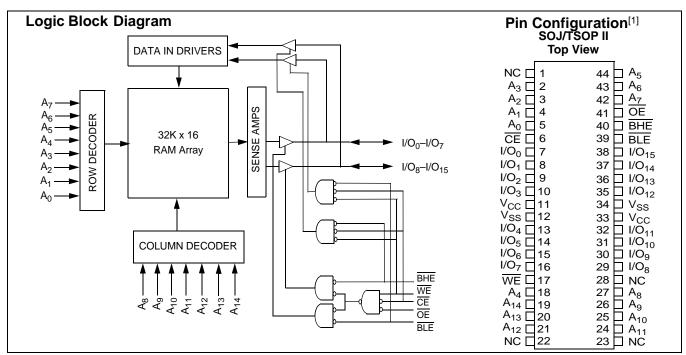
Writing to the device is <u>acc</u>omplished by taking chip enable (\overline{CE}) and write enable (\overline{WE}) inputs LOW. If byte low enable (\overline{BLE}) is LOW, then data from I/O pins $(I/O_0$ through $I/O_7)$, is written into the location specified <u>on the address pins</u> $(A_0$ through $A_{14})$. If byte high enable (\overline{BHE}) is LOW, then data from I/O pins $(I/O_8$ through $I/O_{15})$ is written into the location specified on the address pins $(A_0$ through $A_{14})$.

Reading <u>from</u> the device is accomplished by taking chip enable (CE) <u>and</u> output enable (OE) LOW <u>while</u> forcing the write enable (WE) HIGH. If byte low enable (BLE) is LOW, then data from the memory location specified by the <u>add</u>ress pins will appear on I/O $_0$ to I/O $_7$. If byte high enable (BHE) is LOW, then data from memory will appear on I/O $_8$ to I/O $_15$. See the truth table at the back of this data sheet for a complete description of read and write modes.

The input/output pins (I/O $_0$ through I/O $_{15}$) are placed in a high-impedance state when the <u>device</u> is desel<u>ected</u> (CE_HIGH), the <u>outputs are disabled</u> (OE HIGH), the BHE and BLE are disable<u>d</u> (BHE, BLE HIGH), or during a write operation (CE LOW, and WE LOW).

The CY7C1020DV33 is available in Pb-free 44-pin 400-Mil wide Molded SOJ and 44-pin TSOP II packages.

For a complete list of related documentation, click here.



Notes

1. NC pins are not connected on the die.



Selection Guide

| | -10 (Industrial) | Unit |
|------------------------------|------------------|------|
| Maximum access time | 10 | ns |
| Maximum operating current | 60 | mA |
| Maximum CMOS standby current | 3 | mA |

Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.) Storage temperature-65 °C to +150 °C Ambient temperature with power applied –55 °C to +125 °C Supply voltage on V_{CC} to Relative $GND^{[2]}$...-0.5 V to +4.6 V DC voltage applied to outputs in High-Z State $^{[2]}$-0.5 V to V_{CC} + 0.5 V

| DC input voltage ^[2] | $-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$ |
|--|--|
| Current into outputs (LOW) | 20 mA |
| Static discharge voltage(per MIL-STD-883, Method 3015) | > 2001 V |
| Latch-up current | > 200 mA |

Operating Range

| Range | Ambient Temperature | V _{CC} | Speed |
|------------|------------------------|-----------------------------------|-------|
| Industrial | –40 °C to +85 °C | $3.3 \text{ V} \pm 0.3 \text{ V}$ | 10 ns |

Electrical Characteristics Over the Operating Range

| Doromotor | Decerinties | Test Conditions | | –10 (In | dustrial) | l lmi4 |
|------------------|--|--|--------------------------|---------|-----------------------|--------|
| Parameter | Description | rest Conditions | | Min. | Max. | Unit |
| V _{OH} | Output HIGH voltage | V_{CC} = Min., I_{OH} = -4.0 mA | | 2.4 | | V |
| V _{OL} | Output LOW voltage | $V_{CC} = Min., I_{OL} = 8.0 \text{ mA}$ | | | 0.4 | V |
| V _{IH} | Input HIGH voltage | | | 2.0 | V _{CC} + 0.3 | V |
| V _{IL} | Input LOW voltage ^[2] | | | -0.3 | 0.8 | V |
| I _{IX} | Input Load current | $GND \le V_1 \le V_{CC}$ | $GND \le V_I \le V_{CC}$ | | +1 | μΑ |
| I _{OZ} | Output leakage current | $GND \le V_1 \le V_{CC}$, Output Disable | ed | -1 | +1 | μА |
| I _{CC} | V _{CC} operating | V _{CC} = Max., | 100 MHz | | 60 | mA |
| | supply current | $I_{OUT} = 0 \text{ mA},$ $f = f_{MAX} = 1/t_{RC}$ | 83 MHz | | 55 | mA |
| | | | 66 MHz | | 45 | mA |
| | | | 40 MHz | | 30 | mA |
| I _{SB1} | Automatic CE Power-down Current—TTL Inputs | Max. V_{CC} , $\overline{CE} \ge V_{IH}$ $V_{IN} \ge V_{IH}$ or $V_{IN} \le V_{IL}$, $f = f_{MAX}$ | | | 10 | mA |
| I _{SB2} | Automatic CE Power-down Current—CMOS Inputs | $\begin{array}{l} \text{Max. V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \\ \text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \text{ or V}_{\text{IN}} \leq 0.3 \text{ V} \end{array}$ | /, f = 0 | | 3 | mA |

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Notes 2. V_{IL} (min.) = -2.0 V and V_{IH} (max) = V_{CC} + 1 V for pulse durations of less than 5 ns.



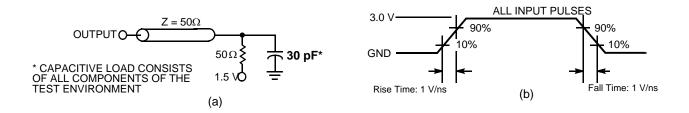
Capacitance^[3]

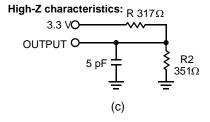
| Parameter | Description Test Conditions | | Max. | Unit |
|------------------|-----------------------------|---|------|------|
| C _{IN} | Input capacitance | $T_A = 25^{\circ}C$, $f = 1$ MHz, $V_{CC} = 3.3$ V | 8 | pF |
| C _{OUT} | Output capacitance | | 8 | pF |

Thermal Resistance^[3]

| Parameter | Description | Test Conditions | SOJ | TSOP II | Unit |
|-----------------|---------------------------------------|---|-------|---------|------|
| Θ_{JA} | | Still air, soldered on a 3 × 4.5 inch, four-layer printed circuit board | 59.52 | 53.91 | °C/W |
| Θ _{JC} | Thermal resistance (Junction to Case) | | 36.75 | 21.24 | °C/W |

AC Test Loads and Waveforms[4]





Notes

- 3. Tested initially and after any design or process changes that may affect these parameters.
- 4. AC characteristics (except High-Z) are tested using the load conditions shown in Figure (a). High-Z characteristics are tested for all speeds using the test load shown in Figure (c).



Switching Characteristics Over the Operating Range [5]

| | 5 | -10 (Inc | dustrial) | |
|---|---|----------|-----------|------|
| Parameter | Description | Min. | Max. | Unit |
| Read Cycle | | 1 | - | 1 |
| t _{power} ^[6] | V _{CC} (typical) to the first access | 100 | | μS |
| t _{RC} | Read cycle time | 10 | | ns |
| t _{AA} | Address to data valid | | 10 | ns |
| t _{OHA} | Data Hold from Address Change | 3 | | ns |
| t _{ACE} | CE LOW to data valid | | 10 | ns |
| t _{DOE} | OE LOW to data valid | | 5 | ns |
| t _{LZOE} | OE LOW to Low-Z ^[7] | 0 | | ns |
| t _{HZOE} | OE HIGH to High-Z ^[7, 8] | | 5 | ns |
| t _{LZCE} | CE LOW to Low-Z ^[7] | 3 | | ns |
| t _{HZCE} | CE HIGH to High-Z ^[7, 8] | | 5 | ns |
| t _{PU} ^[9] | CE LOW to Power-up | 0 | | ns |
| t _{PD} ^[9] | CE HIGH to Power-down | | 10 | ns |
| t _{DBE} | Byte enable to data valid | | 5 | ns |
| t _{LZBE} | Byte enable to low-Z | 0 | | ns |
| t _{HZBE} | Byte disable to high-Z | | 5 | ns |
| Write Cycle ^[10, 11] | | 1 | -1 | 1 |
| t _{WC} | Write cycle time | 10 | | ns |
| t _{SCE} | CE LOW to write end | 8 | | ns |
| t _{AW} | Address set-up to write end | 8 | | ns |
| t _{HA} | Address hold from write end | 0 | | ns |
| t _{SA} | Address set-up to write start | 0 | | ns |
| t _{PWE} | WE pulse width | 7 | | ns |
| t _{SD} | Data set-up to write end | 5 | | ns |
| t _{HD} | Data hold from write end | 0 | | ns |
| t _{LZWE} WE HIGH to Low-Z ^[7] | | 3 | | ns |
| t _{HZWE} | WE LOW to High-Z ^[7, 8] | | 5 | ns |
| t _{BW} | Byte enable to end of write | 7 | | ns |

Notes

- 5. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V.

 6. t_{POWER} gives the minimum amount of time that the power supply should be at typical V_{CC} values until the first memory access can be performed

 7. t_{HZOE}, t_{HZBE}, t_{HZCE}, and t_{HZWE} are specified with a load capacitance of 5 pF as in (c) of AC Test Loads. Transition is measured when the outputs enter a high impedance state.

 8. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZCE}, and t_{HZWE} for any given device.

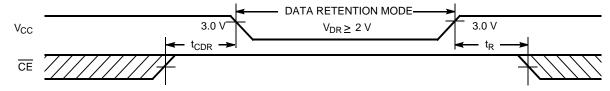
- This parameter is guaranteed by design and is not tested.
 The internal Write time of the memory is defined by the overlap of CE LOW, WE LOW and BHE/BLE LOW. CE, WE and BHE/BLE must be LOW to initiate a Write and the transition of these signals can terminate the Write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the Write.
 The minimum write cycle time for Write Cycle 3 (WE controlled, OE LOW) is the sum of thzwe and tsp.



Data Retention Characteristics (Over the Operating Range)

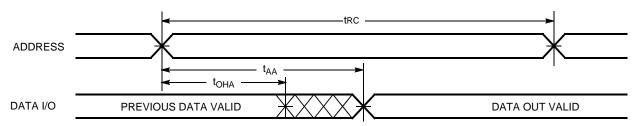
| Parameter | Description | Conditions | Min. | Max. | Unit |
|--------------------------------|--------------------------------------|---|-----------------|------|------|
| V_{DR} | V _{CC} | | 2.0 | | V |
| I _{CCDR} | Data retention current | $V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V},$ Industrial $V_{IN} \ge V_{CC} - 0.3 \text{ V}$ or $V_{IN} \le 0.3 \text{ V}$ | | 3 | mA |
| t _{CDR} [3] | Chip deselect to data retention time | | 0 | | ns |
| t _R ^[12] | Operation recovery time | | t _{RC} | | ns |

Data Retention Waveform

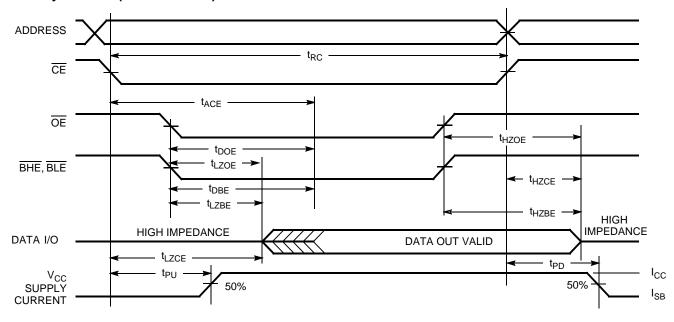


Switching Waveforms

Read Cycle No. 1 (Address Transition Controlled)[13, 14]



Read Cycle No. 2 (OE Controlled)[14, 15]



- 12. Full device operation requires lin<u>ear V_{CC} ramp</u> from V_{DR} to V_{CC(min.)} ≥ 50 μs or stable at V_{CC(min.)} ≥ 50 μs.

 13. Device is continuously selected. OE, CE, BHE and/or BLE = V_{IL}.

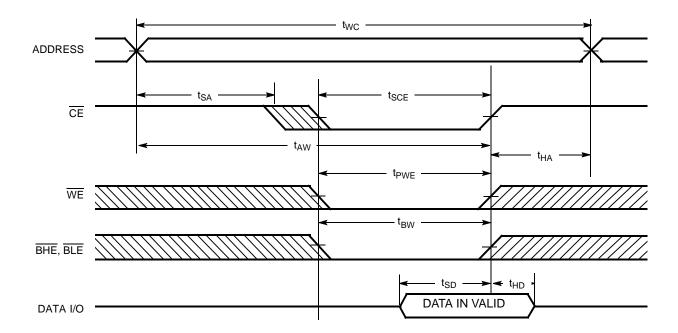
 14. WE is HIGH for Read cycle.

 15. Address valid prior to or coincident with CE transition LOW.

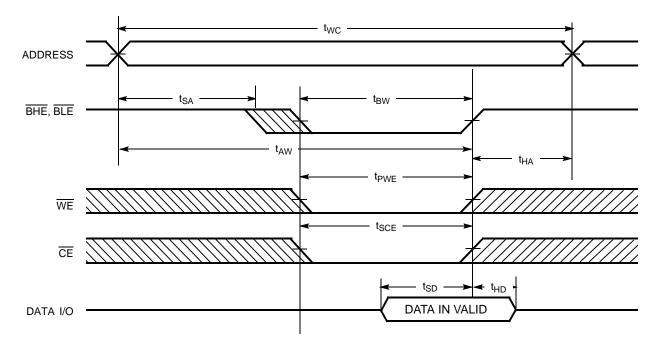


Switching Waveforms (continued)

Write Cycle No. 1 (CE Controlled)[16, 17]



Write Cycle No. 2 (BLE or BHE Controlled)



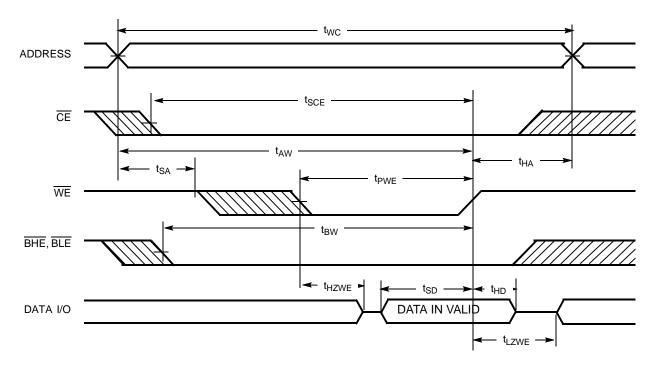
^{16.} Data I/O is high impedance if \overline{OE} or \overline{BHE} and/or $\overline{BLE} = V_{IH}$.

17. If \overline{CE} goes HIGH simultaneously with \overline{WE} going HIGH, the output remains in a high-impedance state.



Switching Waveforms (continued)

Write Cycle No. 3 (WE Controlled, OE LOW)



Truth Table

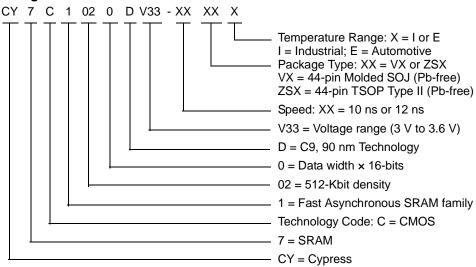
| CE | OE | WE | BLE | BHE | I/O ₀ -I/O ₇ | I/O ₈ –I/O ₁₅ | Mode | Power |
|----|----|----|-----|-----|------------------------------------|-------------------------------------|----------------------------|----------------------------|
| Н | Х | Х | X | X | High-Z | High-Z | Power-down | Standby (I _{SB}) |
| L | L | Н | L | L | Data Out | Data Out | Read—All bits | Active (I _{CC}) |
| | | | L | Н | Data Out | High-Z | Read—Lower bits only | Active (I _{CC}) |
| | | | Н | L | High-Z | Data Out | Read—Upper bits only | Active (I _{CC}) |
| L | Х | L | L | L | Data In | Data In | Write—All bits | Active (I _{CC}) |
| | | | L | Н | Data In | High-Z | Write—Lower bits only | Active (I _{CC}) |
| | | | Н | L | High-Z | Data In | Write—Upper bits only | Active (I _{CC}) |
| L | Н | Н | Х | Х | High-Z | High-Z | Selected, Outputs Disabled | Active (I _{CC}) |
| L | Х | Х | Н | Н | High-Z | High-Z | Selected, Outputs Disabled | Active (I _{CC}) |



Ordering Information

| Speed (ns) | Ordering Code | Package Name | Package Type | Operating Range |
|------------|---------------------|--------------|-------------------------------|-----------------|
| 10 | CY7C1020DV33-10ZSXI | 51-85087 | 44-pin TSOP Type II (Pb-free) | Industrial |

Ordering Code Definitions

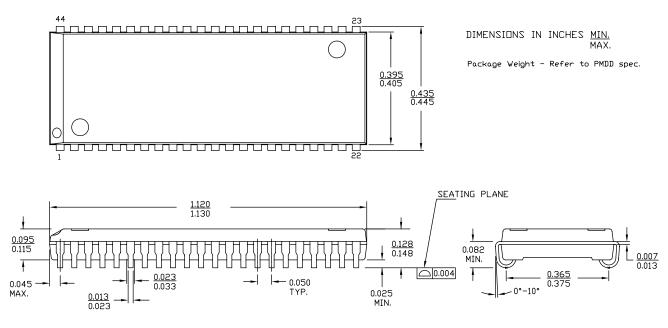


Shaded areas contain advance information. Please contact your local Cypress sales representative for availability of these parts.



Package Diagrams

Figure 1. 44-pin (400-Mil) Molded SOJ (51-85082)

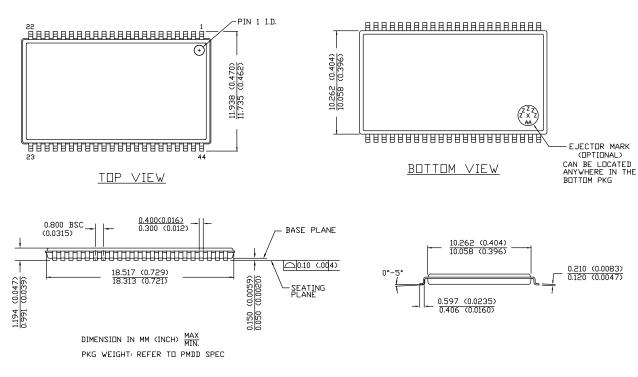


51-85082 *E



Package Diagrams (continued)

Figure 2. 44-Pin Thin Small Outline Package Type II (51-85087)



51-85087 *E



Acronyms

| Acronym | Description |
|---------|---|
| BHE | byte high enable |
| BLE | byte low enable |
| CE | chip enable |
| CMOS | complementary metal oxide semiconductor |
| I/O | input/output |
| ŌĒ | output enable |
| SRAM | static random access memory |
| TSOP | thin small outline package |
| WE | write enable |

Document Conventions

Units of Measure

| Symbol | Unit of Measure |
|--------|-----------------|
| °C | degrees Celsius |
| μΑ | microamperes |
| mA | milliamperes |
| MHz | megahertz |
| ns | nanoseconds |
| pF | picofarads |
| V | volts |
| Ω | ohms |
| W | watts |



Document History Page

| REV. | ECN NO. | Issue Date | Orig. of Change | Description of Change |
|------|---------|------------|--------------------|--|
| ** | 201560 | See ECN | SWI | Advance Information data sheet for C9 IPP |
| *A | 233695 | See ECN | RKF | DC parameters modified as per EROS (Spec # 01-02165) Pb-free Offering in Ordering Information |
| *B | 262950 | See ECN | RKF | Changed I/O ₁ – I/O ₁₆ to I/O ₀ – I/O ₁₅ Added Data Retention Characteristics table Added T _{power} spec in Switching Characteristics table Added 44-SOJ package diagram Shaded Ordering Information |
| *C | 307596 | See ECN | RKF | Reduced Speed bins to -8 and -10 ns |
| *D | 560995 | See ECN | VKN | Converted from Preliminary to Final Removed Commercial operating range Removed 8 ns speed bin Added Automotive information Added I _{CC} values for the frequencies 83MHz, 66MHz and 40MHz Updated Thermal Resistance table Updated Ordering Information table Changed Overshoot spec from V _{CC} +2 V to V _{CC} +1 V in footnote #4 |
| *E | 2898399 | 03/24/2010 | AJU | Updated Package Diagrams |
| *F | 3109992 | 12/14/2010 | AJU | Added Ordering Code Definitions. |
| *G | 3424450 | 10/28/2011 | TAVA | Updated footnotes Updated Selection Guide, Operating Range, Electrical Characteristics Over the Operating Range, Switching Characteristics Over the Operating Range [5], Data Retention Characteristics (Over the Operating Range), Switching Waveforms, and Ordering Information. Updated Package Diagrams Added Acronyms, and Document Conventions |
| *H | 3861347 | 01/08/2013 | TAVA | Updated Ordering Information (Updated part numbers). Updated Package Diagrams: spec 51-85082 – Changed revision from *D to *E. spec 51-85087 – Changed revision from *D to *E. |
| * | 4574311 | 11/19/2014 | TAVA | Added related documentation hyperlink in page 1. Added note 11 in Switching Characteristics Over the Operating Range [5]. Added note reference in the Switching Characteristics table. |



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